

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/500,511	BADYLAK ET AL.
	Examiner	Art Unit
	Shin-Lin Chen	1632

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
424	574	10/1/2010	SLC
424	572	10/1/2010	SLC
424	520	10/1/2010	SLC
424/553		10/1/2010	SLC